

GPMD3130A

Dual N-Channel Enhancement Mode MOSFETSFET

Preliminary

May. 05, 2014

Version 0.1

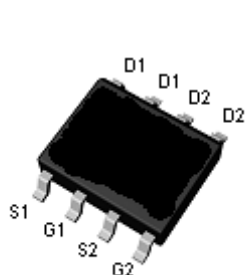
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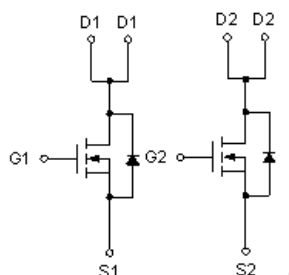
Dual N-Channel Enhancement Mode MOSFETSFET

1. FEATURES

- **30V/10A,**
 - $R_{DS(ON)}=13m\Omega$ (max.) @ $V_{GS}= 10V$
 - $R_{DS(ON)}=17m\Omega$ (max.) @ $V_{GS}= 4.5V$
- **Reliable and Rugged**
- **Lead Free and Green Devices Available**
 - (RoHS Compliant)
- **100% UIS Tested**
- **Applications**
 - Power Management in Notebook Computer, Portable Equipment and Battery Powered Systems.
- **Pin Description**



Top View of SOP-8



P Channel MOSFET

2. ORDERING AND MARKING INFORMATION

2.1. Ordering Information

Product Number	Package Type	Packing Information
GPMD3130A–HS01X	Green Package	Tube
GPMD3130A –T	-	Wafer
GPMD3130A–EHS01x	Green Package	Tape and Reel

GPM D3130A – H S01 1

- └─ Package serial number
- └─ S01: SOP8 package type
- └─ H: green package with tube packing

3. ABSOLUTE MAXIMUM RATINGS

Absolute Maximum Ratings (TA=25°C Unless Otherwise Noted)

Symbol	Parameter		Rating	Unit
V_{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		±20	
I_D^a	Continuous Drain Current ($V_{GS}=10V$)	$T_A=25^\circ C$	10	A
		$T_A=70^\circ C$	8	
I_{DM}^a	300µs Pulsed Drain Current ($V_{GS}=10V$)		40	
I_S^a	Diode Continuous Forward Current		1	
I_{AS}^b	Avalanche Current (Single Pulse)		23	
E_{AS}^b	Avalanche Energy, Single Pulse ($L=0.1mH$)		25	mJ
T_J	Maximum Junction Temperature		150	°C
T_{STG}	Storage Temperature Range		-55 to 150	
P_D^a	Maximum Power Dissipation	$T_A=25^\circ C$	1.7	W
		$T_A=70^\circ C$	1.08	
$R_{JA}^{a,c}$	Thermal Resistance-Junction to Ambient	$t \leq 10s$	48	°C/W
		Steady State	74	
R_{JL}	Thermal Resistance-Junction to Lead	Steady State	32	

Note a : Surface Mounted on 1in² pad area, $t \leq 10sec$. Maximum Power dissipation is calculated from R_{JA} (worst) =62.5°C/W under $t \leq 10s$.

Note b : UIS tested and pulse width limited by maximum junction temperature 150°C (initial temperature $T_J=25^\circ C$).

Note c : Maximum under Steady State conditions is 90 °C/W.

4.ELECTRICAL CHARACTERISTICS

Electrical Characteristics (T_A=25°C Unless Otherwise Noted)

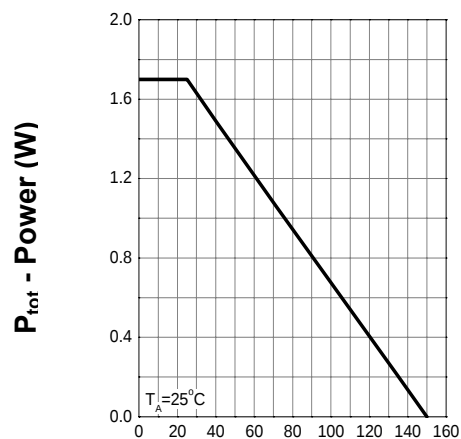
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250μA	30	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =24V, V _{GS} =0V	-	-	1	μA
		T _J =85°C	-	-	30	
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	1.3	1.9	2.5	V
I _{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
R _{DS(ON)} ^a	Drain-Source On-state Resistance	V _{GS} =10V, I _{DS} =12A	-	10.5	13	mΩ
		V _{GS} =4.5V, I _{DS} =10A	-	13	17	
G _{fs}	Forward Transconductance	V _{DS} =5V, I _{DS} =20A	-	50	-	S
Diode Characteristics						
V _{SD} ^a	Diode Forward Voltage	I _{SD} =1A, V _{GS} =0V	-	0.7	1.1	V
t _{rr} ^b	Reverse Recovery Time	I _{SD} =10A, dI _{SD} /dt=100A/μs	-	19	-	ns
Q _{rr} ^b	Reverse Recovery Charge		-	10	-	nC
Dynamic Characteristics ^b						
R _G	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=1MHz	-	2.5	-	Ω
C _{iss}	Input Capacitance	V _{GS} =0V,	-	770	-	pF
C _{oss}	Output Capacitance	V _{DS} =15V,	-	130	-	
C _{rss}	Reverse Transfer Capacitance	Frequency=1.0MHz	-	76	-	
t _{d(ON)}	Turn-on Delay Time	V _{DD} =15V, R _L =15Ω, I _{DS} =1A, V _{GEN} =10V, R _G =6Ω	-	8	14	ns
t _r	Turn-on Rise Time		-	10	17	
t _{d(OFF)}	Turn-off Delay Time		-	23	42	
t _f	Turn-off Fall Time		-	4.5	12	
Gate Charge Characteristics ^b						
Q _g	Total Gate Charge	V _{DS} =15V, V _{GS} =10V, I _{DS} =10A	-	14	18	nC
	Total Gate Charge		-	6.3	-	
Q _{gs}	Gate-Source Charge	V _{DS} =15V, V _{GS} =4.5V, I _{DS} =10A	-	2.9	-	
Q _{gd}	Gate-Drain Charge		-	2	-	

Note a : Pulse test ; pulse width ≤ 300 μs, duty cycle ≤ 2%.

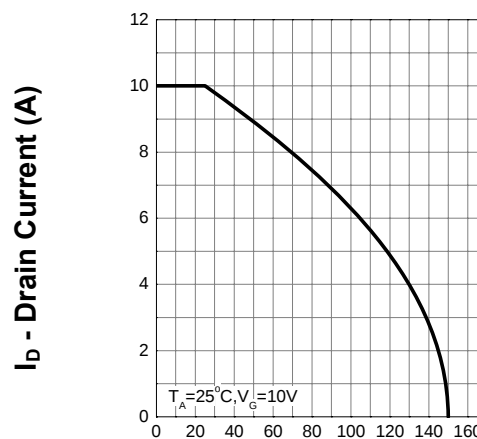
Note b : Guaranteed by design, not subject to production testing.

5. TYPICAL OPERATING CHARACTERISTICS

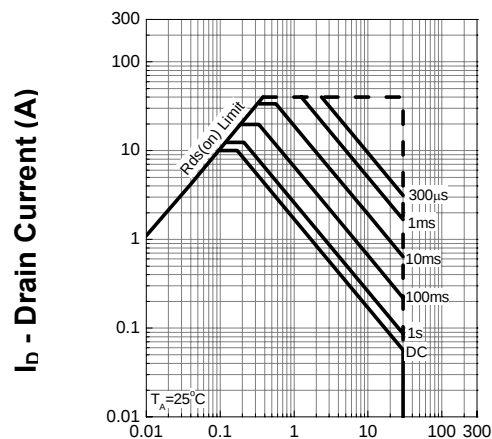
Power Dissipation


 T_j - Junction Temperature ($^\circ\text{C}$)

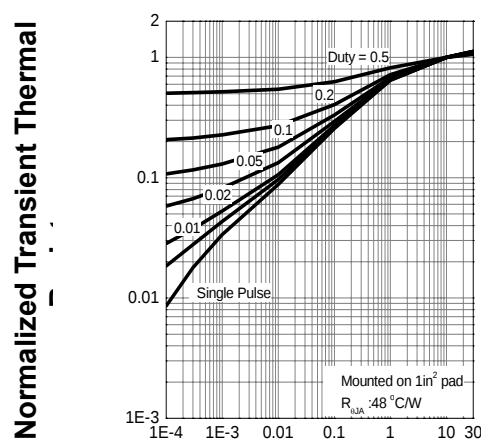
Drain Current


 T_j - Junction Temperature ($^\circ\text{C}$)

Safe Operation Area


 V_{DS} - Drain-Source Voltage (V)

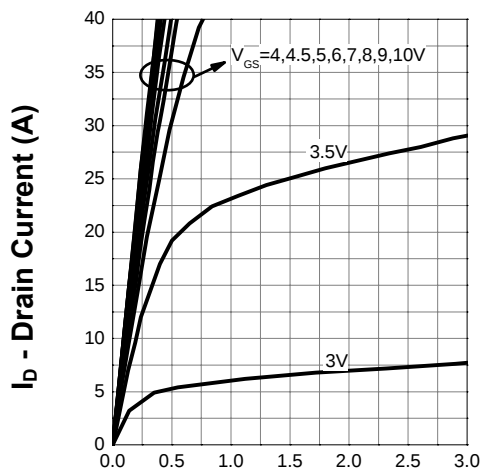
Thermal Transient Impedance



Square Wave Pulse Duration (sec)

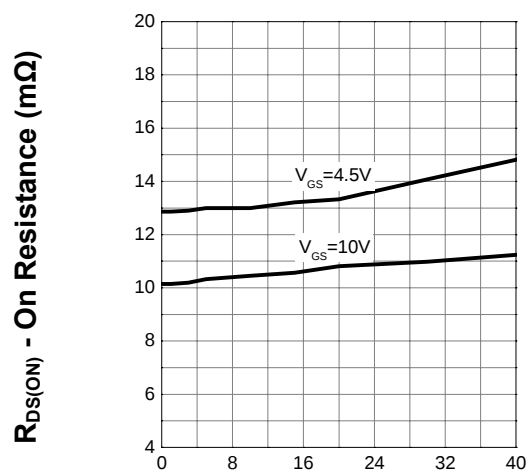
6. TYPICAL OPERATING CHARACTERISTICS (Cont.)

Output Characteristics



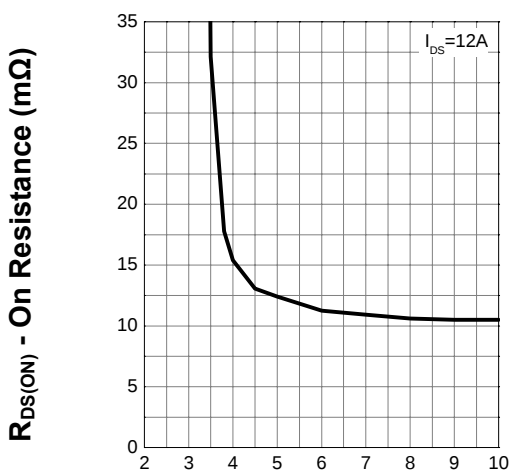
V_{GS} = 4, 4.5, 5, 6, 7, 8, 9, 10V

Drain-Source On Resistance



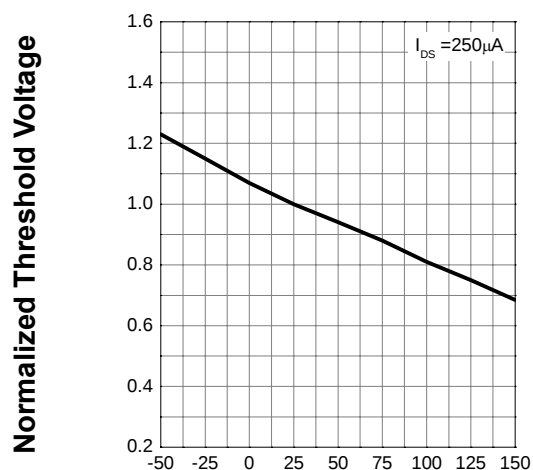
I_D - Drain Current (A)

Gate-Source On Resistance



$I_{DS} = 12A$

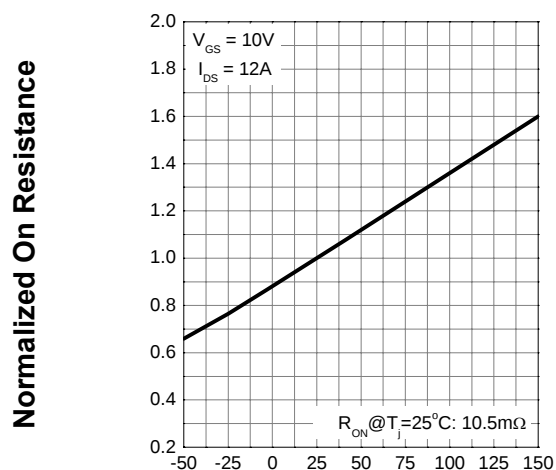
Gate Threshold Voltage



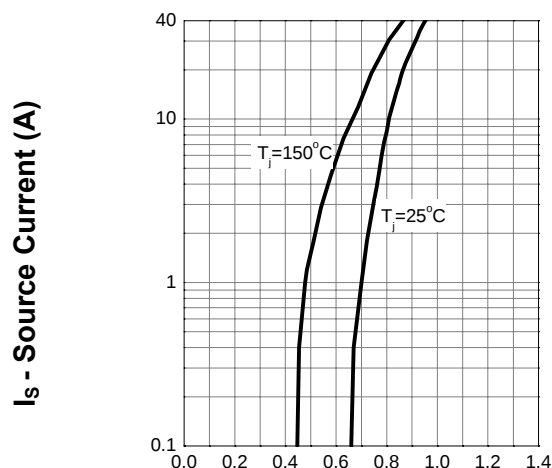
$I_{DS} = 250\mu A$

7. TYPICAL OPERATING CHARACTERISTICS (Cont.)

Drain-Source On Resistance

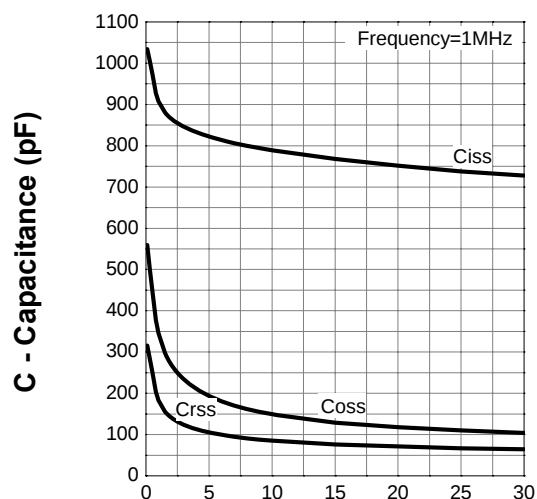


Source-Drain Diode Forward

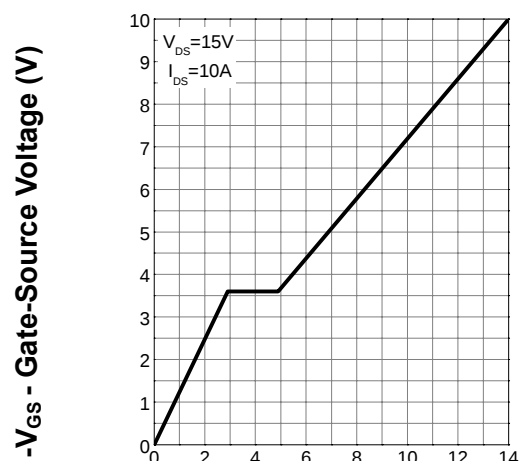

 T_j - Junction Temperature (°C)

 V_{SD} - Source-Drain Voltage (V)

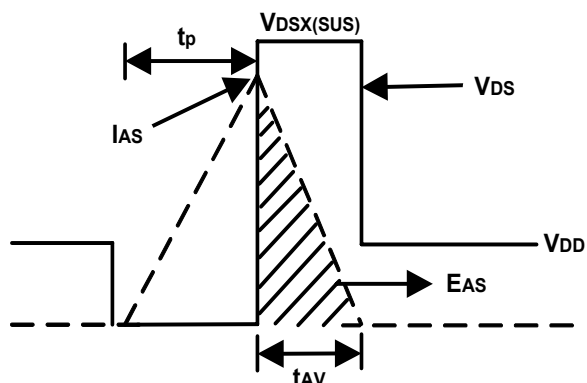
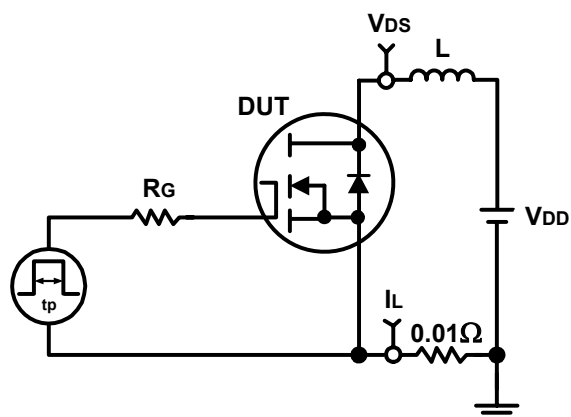
Capacitance


 V_{DS} - Drain-Source Voltage (V)

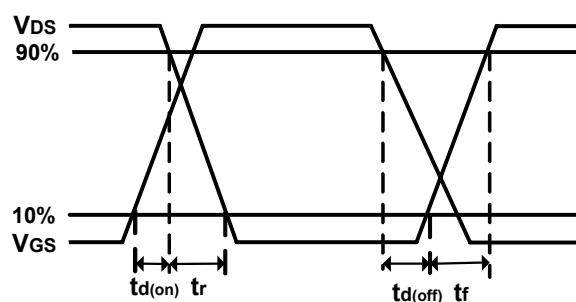
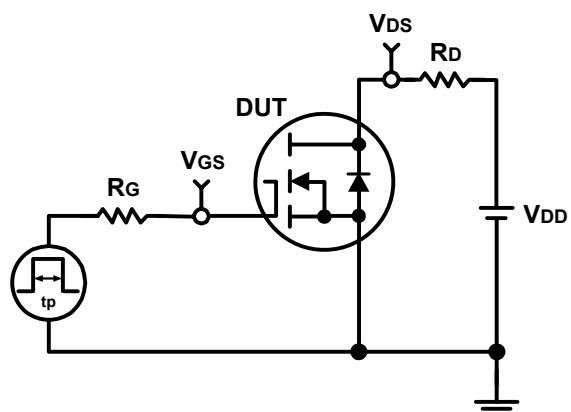
Gate Charge


 Q_G - Gate Charge (nC)

8. AVALANCHE TEST CIRCUIT AND WAVEFORMS

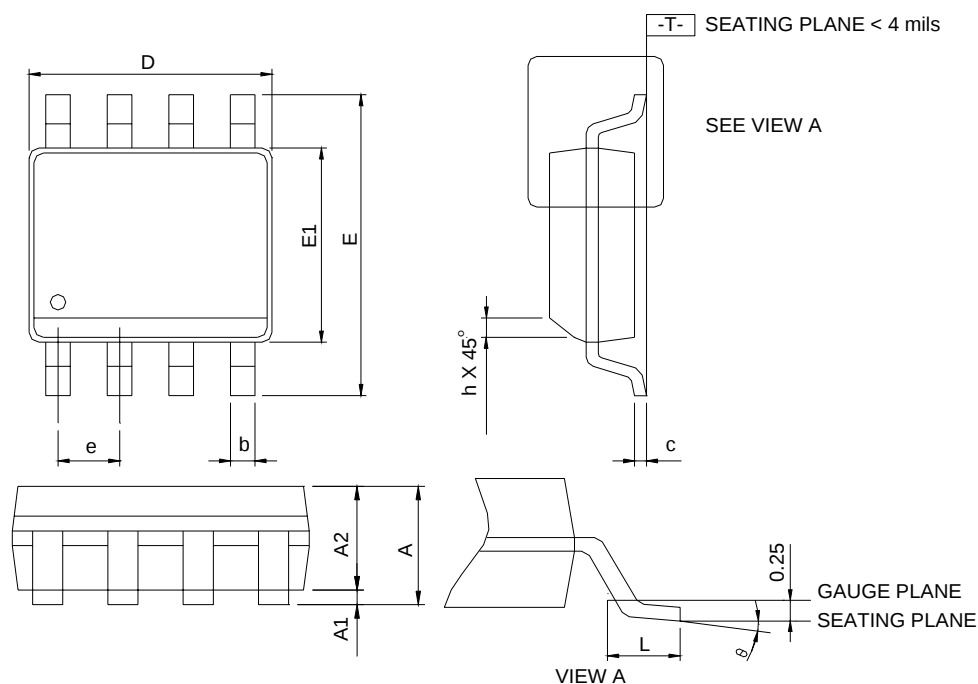


9. SWITCHING TIME TEST CIRCUIT AND WAVEFORMS



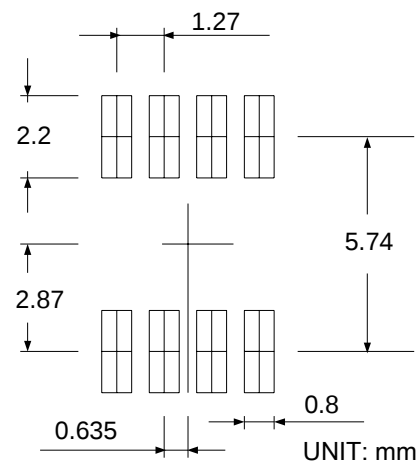
10. PACKAGING INFORMATION

SOP-8



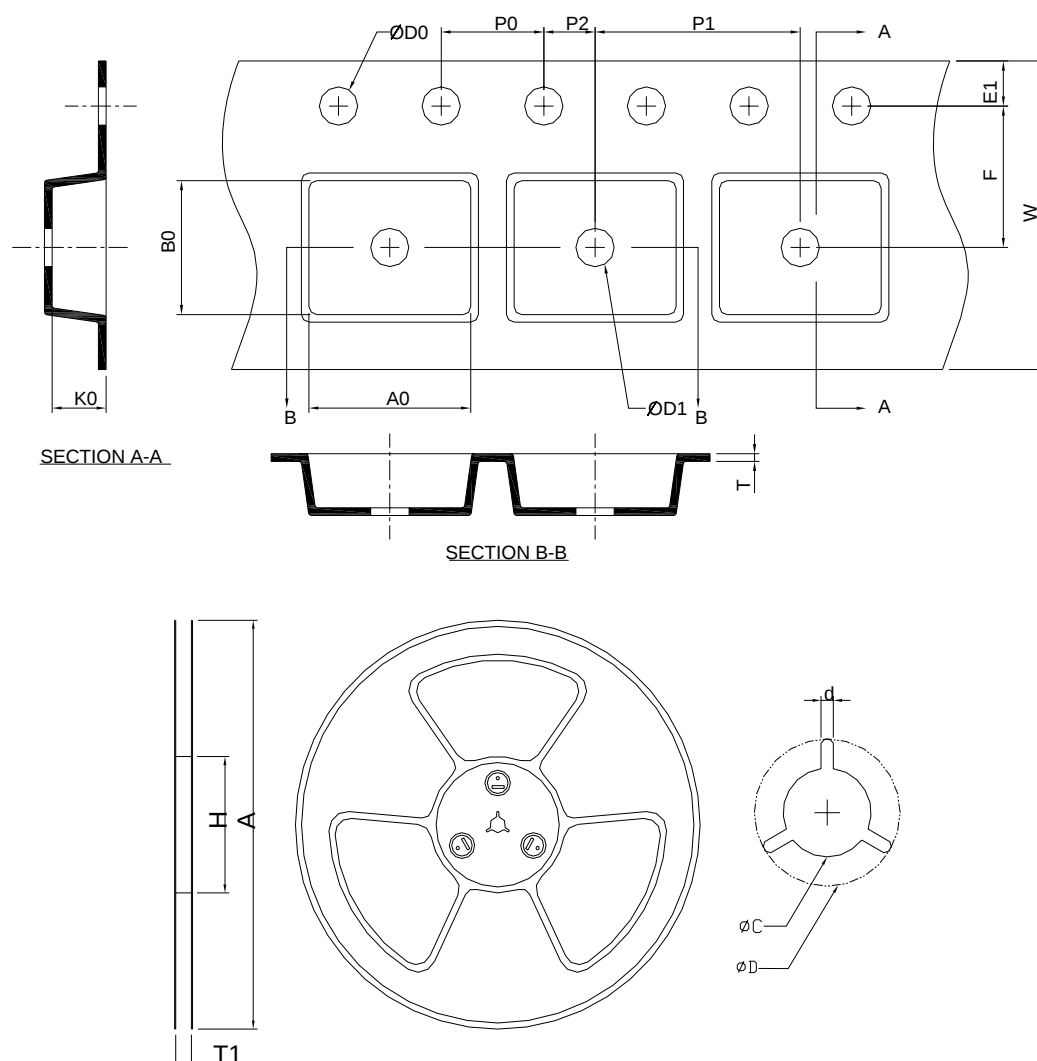
S O P - 8	SOP-8			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	-	1.75	-	0.069
A1	0.10	0.25	0.004	0.010
A2	1.25	-	0.049	-
b	0.31	0.51	0.012	0.020
c	0.17	0.25	0.007	0.010
D	4.80	5.00	0.189	0.197
E	5.80	6.20	0.228	0.244
E1	3.80	4.00	0.150	0.157
e	1.27 BSC		0.050 BSC	
h	0.25	0.50	0.010	0.020
L	0.40	1.27	0.016	0.050
θ	0°	8°	0°	8°

RECOMMENDED LAND PATTERN



- Note: 1. Follow JEDEC MS-012 AA.
 2. Dimension "D" does not include mold flash, protrusions or gate burrs. Mold flash, protrusion or gate burrs shall not exceed 6 mil per side.
 3. Dimension "E" does not include inter-lead flash or protrusions. Inter-lead flash and protrusions shall not exceed 10 mil per side.

11. CARRIER TAPE & REEL DIMENSIONS

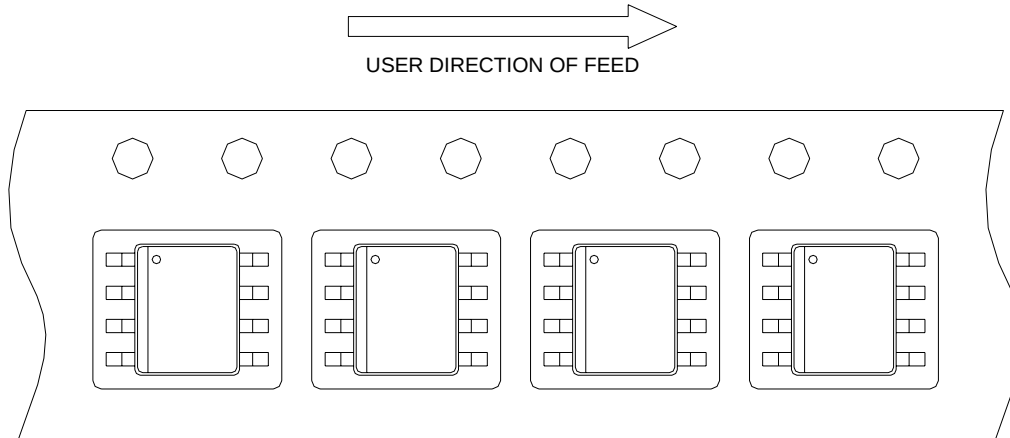


Application	A	H	T1	C	d	D	W	E1	F
SOP-8	330.0±2.00	50 MIN.	12.4+2.00 -0.00	13.0+0.50 -0.20	1.5 MIN.	20.2 MIN.	12.0±0.30	1.75±0.10	5.5±0.05
	P0	P1	P2	D0	D1	T	A0	B0	K0
	4.0±0.10	8.0±0.10	2.0±0.05	1.5+0.10 -0.00	1.5 MIN.	0.6+0.00 -0.40	6.40±0.20	5.20±0.20	2.10±0.20

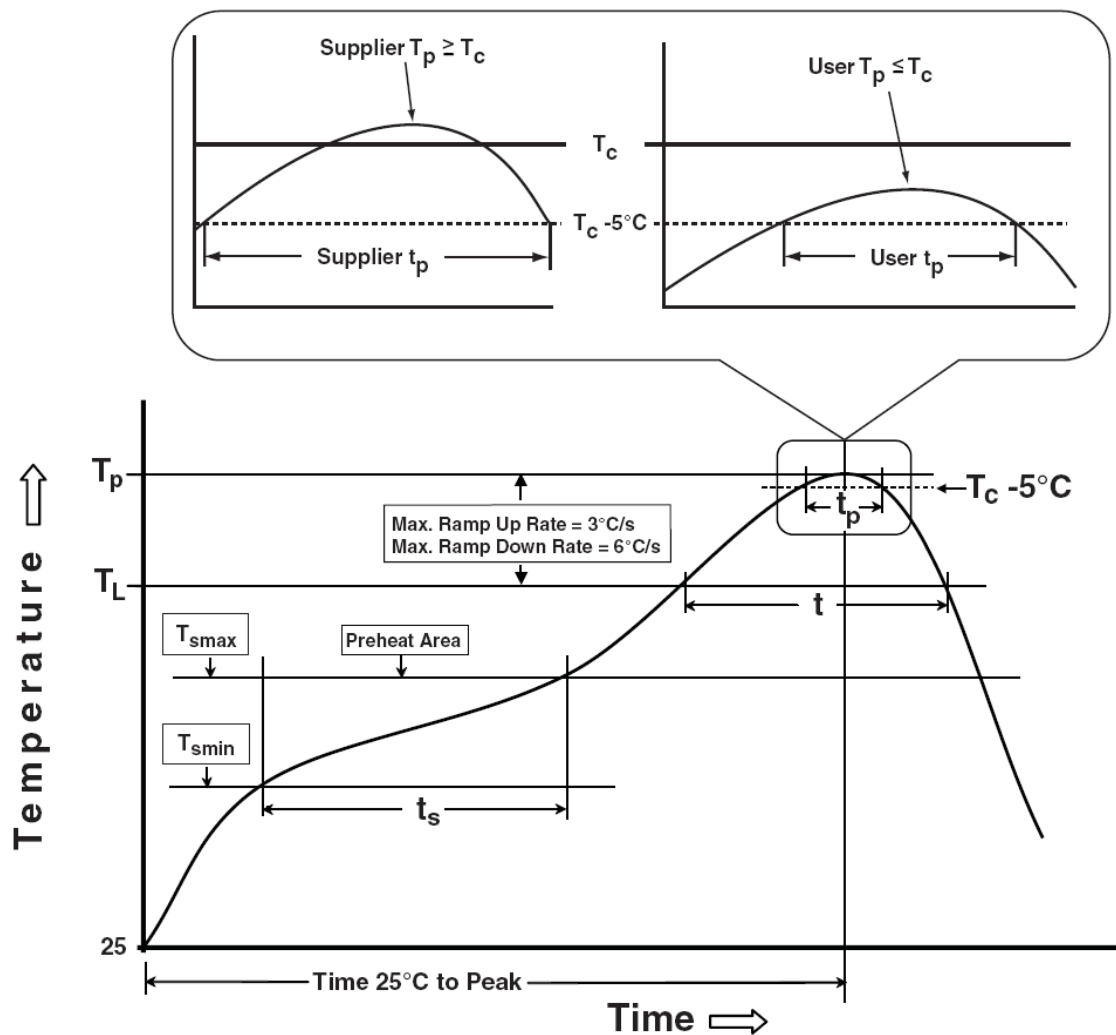
(mm)

12. TAPING DIRECTION INFORMATION

SOP-8



13. CLASSIFICATION PROFILE



14. CLASSIFICATION REFLOW PROFILES

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak		
Temperature min (T_{smin})	100 °C	150 °C
Temperature max (T_{smax})	150 °C	200 °C
Time (T_{smin} to T_{smax}) (t_s)	60-120 seconds	60-120 seconds
Average ramp-up rate (T_{smax} to T_p)	3 °C/second max.	3°C/second max.
Liquidous temperature (T_L)	183 °C	217 °C
Time at liquidous (t_l)	60-150 seconds	60-150 seconds
Peak package body Temperature (T_p)*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t_p)** within 5°C of the specified classification temperature (T_c)	20** seconds	30** seconds
Average ramp-down rate (T_p to T_{smax})	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.
* Tolerance for peak profile Temperature (T_p) is defined as a supplier minimum and a user maximum.		
** Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum.		

Table 1. SnPb Eutectic Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures (T_c)

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

15. RELIABILITY TEST PROGRAM

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	1000 Hrs, 80% of VDS max @ T_{jmax}
HTGB	JESD-22, A108	1000 Hrs, 100% of VGS max @ T_{jmax}
PCT	JESD-22, A102	168 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -65°C~150°C

16. DISCLAIMER

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17. REVISION HISTORY

Date	Revision #	Description	Page
May 05, 2014	0.1	Preliminary Version	16